

16th RD50 Workshop (Barcelona)

Tuesday, 1 June 2010

Full Detector Characterization (14:30 - 19:00)

time	[id] title	presenter
14:30	[6] Campaign to identify the future CMS sensor baseline	HARTMANN, Frank
14:50	[3] Impact of bulk generation current on operation of floating guard rings in silicon segmented detectors	VERBITSKAYA, Elena
15:10	[10] A CCE and TCT study on low resistivity MCz-n detectors	PACIFICO, Nicola
15:30	[13] Characterization of 75 and 150 micron thin strip and pixel sensors produced at MPP-HLL	WEIGELL, Philipp
15:50	[14] Characterization of the n-in-p CiS pixel production	MACCHIOLO, Anna
16:10	[20] Status of the n-in-n CiS pixel production	Mr RUMMLER, André
16:30	coffee break	
16:50	[18] Alibava system upgrade	MARCO HERNANDEZ, Ricardo
17:10	[21] Outlook on the 2010 n-in-n CiS pixel production on thinned silicon	Mr RUMMLER, André
17:30	[15] Annealing effects in irradiated HPK strip detectors measured with SCT128 chip	MANDIC, Igor
17:50	[17] Test beam results of MCz-Si detectors	Dr LUUKKA, Panja-Riina
18:10	[26] Charge collection measurements on irradiated planar silicon strip sensors	WALZ, Michel
18:30	[34] discussion on Full Detector Characterization and current projects	CASSE, Gianluigi